

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2	"6137295".pn. or "6091249".pn.	US-PGPUB; USPAT	OR	ON	2006/07/25 18:27
L2	7675	(250/306,307,310,311,492.3,492.2,492.22).ccls.	US-PGPUB; USPAT	OR	ON	2006/07/25 18:27
L3	7179	(324/750,751,754,158.1,537).ccls.	US-PGPUB; USPAT	OR	ON	2006/07/25 18:28
L4	1100	(356/334,394).ccls.	US-PGPUB; USPAT	OR	ON	2006/07/25 18:28
L5	627	(156/89.12,379).ccls.	US-PGPUB; USPAT	OR	ON	2006/07/25 18:28
L6	16373	L2 or L3 or L4 or L5	US-PGPUB; USPAT	OR	ON	2006/07/25 18:29
L7	198	L6 and ((silicon adj on adj insulator) or SOI)	US-PGPUB; USPAT	OR	ON	2006/07/25 18:32
L8	0	L7 and (semiconductor near2 die) and (inspection with (electron or SEM))	US-PGPUB; USPAT	OR	ON	2006/07/25 18:33
L9	49	L6 and (semiconductor near2 die) and (inspection with (electron or SEM))	US-PGPUB; USPAT	OR	ON	2006/07/25 18:31
L10	0	L9 and ((silicon adj on adj insulator) or SOI)	US-PGPUB; USPAT	OR	ON	2006/07/25 18:31
L11	121	(semiconductor near2 die) and (inspection with (electron or SEM))	US-PGPUB; USPAT	OR	ON	2006/07/25 18:31
L12	126	(semiconductor near2 die) and (inspection with (electron or SEM))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/25 18:32
L13	0	L12 and ((silicon adj on adj insulator) or SOI)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/25 18:32
L14	23	(semiconductor near2 die) and (inspection with (electron or SEM)).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/25 18:32

## EAST Search History

L15	0	L14 and ((silicon adj on adj insulator) or SOI).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/25 18:32
L16	22	L6 and ((silicon adj on adj insulator) or SOI).clm.	US-PGPUB; USPAT	OR	ON	2006/07/25 18:32
L17	0	L16 and (semiconductor near2 die) and (inspection with (electron or SEM)).clm.	US-PGPUB; USPAT	OR	ON	2006/07/25 18:33
L18	1381	((250/492.3)).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/07/25 18:34